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Since the foundation in 1990, the company FOCUS GmbH is engaged in the development and creation of instruments for electron spectroscopy and surface analysis. The main part of the FOCUS products is distributed all over the world by the company OMICRON GmbH in Taunusstein/Germany.

The product range includes usual surface science instruments like electron spectrometers and VUV-light sources. Beside the evaporators, which are used for the preparation of nanoscaled structures, FOCUS has developed a nanoanalytic instrument, the **FOCUS PEEM**. It is a compact photoelectron microscope, which is used for the electron optical mapping of surfaces down to the resolution range of 40 nm. The instrument can be enhanced by an optional energy filter, which introduce simple methods for energy selective PEEM imaging (spectromicroscopy) and spectra of local energy distribution (microspectroscopy). A high performance filter is invented as the PEEM Nano-ESCA system. The instrument is at present under further development to allocate a standard for nanoanalytic and science. On the one hand stands the enhancement of the lateral resolution, on the other hand there is the opening of a new application range beside the classical surface science and magnetism. The application of the PEEM together with other nanoanalytic instruments like STM/AFM is warranted by compatible sample transfer systems. The PEEM can be used for visualisation of nanoscaled workfunction contrast, magnetic surface domains and lateral distribution of compounds.

The patented instrument **FOCUS-SPLEED**, a detector for spin analysis of electrons, enables together with a scanning electron microscope the imaging of nanoscaled magnetic domains (**SEMPA**).